

Special Issue

Surface Technology: Laser in Trace Analysis and Precision Measurements

Message from the Guest Editors

We are inviting submissions to the Special Issue on Laser Application in Trace Analysis and Precision Measurements. Through the interaction of laser with molecules, atoms, and nucleus, the trace analysis and precision measurements technologies of physical and chemical material are formed, which have great application prospects in the frontier fields of biology, geology, energy, environment, space, and so on. In recent years, facing the new requirement brought by the development of advanced manufacturing of precision measurement, scientific research institutions have engaged in in-depth scientific researches on common issues of principle and method for measuring system. In addition, in the field of laser application, the breakthroughs on trace analysis and precision measurements formed novelty measuring theory, method, and instrument. In this Special Issue, we invite submissions exploring cutting-edge research and recent advances in the fields of laser application in trace analysis and precision measurements.

- new theory and principle
- method and technology
- key component development
- measuring instrument
- data evaluation and processing
- laser application

Guest Editors

Prof. Dr. Chen Chen

College of Instrumentation & Electrical Engineering, Jilin University, Changchun 130061, China

Prof. Dr. Guang Yang

College of Instrumentation & Electrical Engineering, Jilin University, Changchun 130061, China

Deadline for manuscript submissions

closed (31 October 2023)



Applied Sciences

an Open Access Journal
by MDPI

Impact Factor 2.5
CiteScore 5.5



mdpi.com/si/112186

Applied Sciences
Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland
Tel: +41 61 683 77 34
appls@mdpi.com

[mdpi.com/journal/
appls](https://mdpi.com/journal/appls)





Applied Sciences

an Open Access Journal
by MDPI

Impact Factor 2.5
CiteScore 5.5



[mdpi.com/journal/
applsci](https://mdpi.com/journal/applsci)



About the Journal

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32,
20133 Milano, Italy

Author Benefits

Open Access:

free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility:

indexed within Scopus, SCIE (Web of Science), Ei Compendex, Inspec, CAPlus / SciFinder, and other databases.

Journal Rank:

JCR - Q2 (Engineering, Multidisciplinary) / CiteScore - Q1 (General Engineering)